Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | WATANABE ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,988,015 A	11-1999	Riu, Herve	74/574.2
*	В	US-2006/0264282 A1	11-2006	Moriya et al.	474/094
*	С	US-7,300,372 B2	11-2007	Riu, Herve	474/94
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP 2005299909 A	10-2005	Japan	NOMURA, SHUICHI	
	0	JP 2005133917 A	05-2005	Japan	KAKINUMA, YOSHIKAZU	
	Р	JP 2004108528 A	04-2004	Japan	KINOSHITA et al.	
	Ø	JP 08177874 A	07-1996	Japan	ULRICH et al.	
	R	EP 1382886 A1	01-2004	European Patent	RIU, HERVE	
	S	WO 2004007992 A1	01-2004	World Intellect	RIU, HERVE	
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.